

# Microwave characteristics of mixed phases of $\text{BaTi}_4\text{O}_9$ – $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$ ceramics

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The microwave characteristics of the  $\text{BaTi}_4\text{O}_9$ – $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  system were investigated, including its microstructure and infrared reflection spectroscopy. It was found that this system is entirely composed of two phases,  $\text{BaTi}_4\text{O}_9$  and  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$ , and it is suggested that the lattices of each phase are well matched obliquely at the interface in the sintered ceramics. The dielectric properties are compared with calculated values deduced from the mixing relations of the two components. Furthermore, the infrared reflection spectra of this system were analysed with the factorized form of the dielectric function, for the purpose of studying the applicability of the reflection analysis technique to this mixed phase system.

## 1. Introduction

Most microwave dielectric ceramics used in mobile communication systems and satellite broadcasting systems are composed of a single phase, which has excellent microwave characteristics e.g.  $\text{Ba}(\text{Zn}_{1/3}\text{Ta}_{2/3})\text{O}_3$  [1],  $\text{Ba}_2\text{Ti}_9\text{O}_{20}$  [2] and  $\text{BaSm}_2\text{Ti}_5\text{O}_{14}$  [3].

In order to obtain the desired dielectric properties, the mixing technique of two low loss materials, with positive and negative dielectric temperature coefficients, has become well known. As reported by Paladino [4], zero temperature coefficient of the resonant frequency,  $\tau_f$ , was achieved at an intermediate composition of  $\text{MgTi}_2\text{O}_5$ – $\text{TiO}_2$  system. This approach should have wide applicability, if the proper selection of two compounds is carried out. However, in general, it is not easy to realize a material with intermediate properties in such two components system because of the difficulty in retaining their individual properties at the sintering temperature. Therefore, as a basis for development of a dielectric material system perfectly composed of two compounds, it is necessary to investigate the system's microstructure and dielectric properties.

As one possible selection of two compounds, the  $\text{TiO}_2$ – $\text{Bi}_2\text{O}_3$  system, composed of two phases,  $\text{TiO}_2$  and  $\text{Bi}_2\text{Ti}_4\text{O}_{11}$  has already been investigated; the mixing relation for microwave dielectric properties, particularly, for  $Q$  values, has been examined [5]. As a result, it was found that the  $Q$  values of mixtures are determined from the volume fraction and  $Q$  value of each component; in a similar manner to the dielectric constant and temperature coefficient [4].

In this study, as another possible selection, the microstructure and microwave dielectric properties of the  $\text{BaTi}_4\text{O}_9$ – $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  system is examined. For the microstructure, the ceramic interface, which is considered to influence the dielectric properties on this system, is studied. Furthermore, infrared reflection analysis of this system was carried out to obtain quantitative dielectric data.

## 2. Experimental procedure

Ceramic samples were prepared with high purity  $\text{BaCO}_3$ ,  $\text{TiO}_2$  and  $\text{Pr}_6\text{O}_{11}$ . The powders were weighed to obtain a composition of  $(1-x)\text{-BaTi}_4\text{O}_9\text{-}x\text{-BaPr}_2\text{Ti}_4\text{O}_{12}$  ( $x = 0, 0.17, 0.36, 0.56, 0.77$  and  $1.00$ ), ball milled, dried and calcined at  $1000^\circ\text{C}$  for 2 h. Following the addition of organic binder, the mixture was pressed into pellets and sintered at  $1300\text{--}1550^\circ\text{C}$  for 2 h. The dielectric characteristics of these sintered ceramics were measured using the resonant cavity method in the  $\text{TE}_{018}$  mode [6].

The infrared reflection spectra were obtained using a Fourier transform spectrometer, Broker IFS-113V. A glow-bar lamp was used for measurement from  $50$  to  $4000\text{ cm}^{-1}$ . A polished ceramic was set in the vacuum chamber evacuated to  $1.3\text{ Pa}$ , and the reflectivities were measured relative to the reflectance of an evaporated gold mirror. The incident angle of radiation was  $11^\circ$ , and the spectra were recorded at a resolution of  $1\text{ cm}^{-1}$ .

The reflectance data were transformed to dielectric data with the factorized form proposed by Gervais and Piriou [7], instead of the classical dispersion theory, considering that vibrational modes with

different energy levels should not be equally damped [8]. The frequency-dependent complex dielectric function is then written as

$$\varepsilon = \varepsilon_{\infty} \prod_j \frac{\Omega_{jLO}^2 - \omega^2 + i\gamma_{jLO} \times \omega}{\Omega_{jTO}^2 - \omega^2 + i\gamma_{jTO} \times \omega} \quad (1)$$

where  $\Omega_{jTO}$  and  $\gamma_{jTO}$  are the transverse optic (TO) mode frequency and its damping constant; and  $\Omega_{jLO}$  and  $\gamma_{jLO}$  are the longitudinal optic (LO) mode frequency and its damping constant, respectively. Equation 1 can be regarded as an extended Lyddane–Sachs–Teller (LST) relation [9,10] in which damping terms are induced. Infrared reflection spectra  $R$  were fitted with the aid of Equation 1 together with

$$R = \left| \frac{(\varepsilon^{1/2} - 1)}{(\varepsilon^{1/2} + 1)} \right|^2 \quad (2)$$

The oscillator strength  $\Delta\varepsilon_j$  [8] and the quality factor  $Q$  can then be obtained from

$$\Delta\varepsilon_j = \varepsilon_{\infty} \left( \frac{\Omega_{jLO}^2}{\Omega_{jTO}^2} - 1 \right) \prod_{k \neq j} \frac{\Omega_{kLO}^2 - \Omega_{jTO}^2}{\Omega_{kTO}^2 - \Omega_{jTO}^2} \quad (3)$$

$$Q = 1/\tan \delta = \frac{\varepsilon'}{\varepsilon''} \quad (4)$$

The microwave dielectric loss of each TO mode is calculated by the following equation [11] under the conditions  $\omega^2 \ll \Omega_{jTO}^2$

$$\tan \delta_j = \frac{\Delta\varepsilon_j(\gamma_{jTO} \times \omega)/\Omega_{jTO}^2}{\varepsilon_{\infty} + \sum_i \Delta\varepsilon_i} \propto \frac{\gamma_{jTO} \times \omega}{\Omega_{jTO}^2} \quad (5)$$

### 3. Results and discussion

#### 3.1. Microstructure

It is well known that in the BaO–TiO<sub>2</sub> system numerous phases, e.g. BaTi<sub>3</sub>O<sub>7</sub>, BaTi<sub>4</sub>O<sub>9</sub> and Ba<sub>2</sub>Ti<sub>9</sub>O<sub>20</sub> exist [12]. Furthermore, various phases are also observed in the BaO–TiO<sub>2</sub>–rare earth oxide system [13]. Therefore, phase control is expected to be extremely difficult in such a system. However, it was found that the (1 – x)BaTi<sub>4</sub>O<sub>9</sub>–xBaPr<sub>2</sub>Ti<sub>4</sub>O<sub>12</sub> system given here is composed of only two phases, BaTi<sub>4</sub>O<sub>9</sub> and BaPr<sub>2</sub>Ti<sub>4</sub>O<sub>12</sub>. In fact, no peaks are observed except for those for BaTi<sub>4</sub>O<sub>9</sub> and BaPr<sub>2</sub>Ti<sub>4</sub>O<sub>12</sub>, as shown in the X-ray diffraction (XRD) patterns, Fig. 1. The XRD patterns of pure BaTi<sub>4</sub>O<sub>9</sub> ( $x = 0$ ) and BaPr<sub>2</sub>Ti<sub>4</sub>O<sub>12</sub> ( $x = 1.0$ ), measured as a standard, are almost the same as ones reported previously [14].

From scanning electron microscopy (SEM) observations of polished and thermally-etched (at 1200 °C for 10 min) cross-sections of two ceramic samples ( $x = 0.36$  and  $0.77$  in Fig. 1, respectively), it is obvious that grains can be divided into two classes, grey parts and white parts; and these grains are in coexistence without interference, as illustrated in Fig. 2a, b, as the backscattering electron image. X-ray microanalysis (XMA) shows that grey grains (spot 1 in Fig. 2b) are composed of only BaTi<sub>4</sub>O<sub>9</sub> (spot 2 in Fig. 2b) and the white grains are composed of only BaPr<sub>2</sub>Ti<sub>4</sub>O<sub>12</sub>.

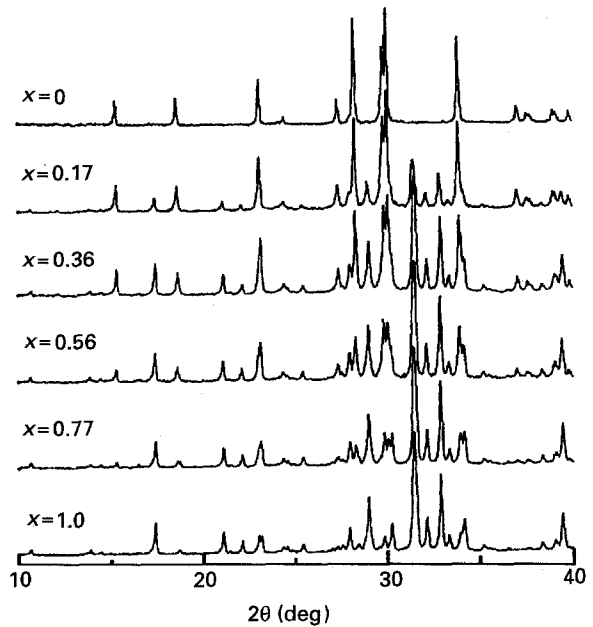


Figure 1 XRD patterns of ceramic samples in the (1 – x)BaTi<sub>4</sub>O<sub>9</sub>–xBaPr<sub>2</sub>Ti<sub>4</sub>O<sub>12</sub> system.

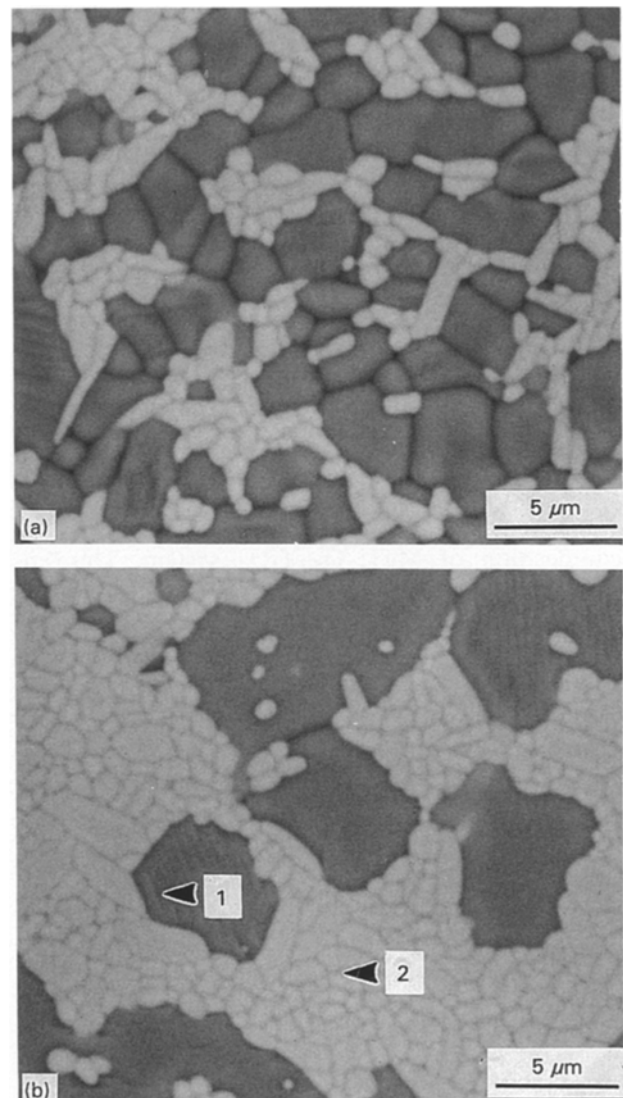


Figure 2 SEM photographs of ceramic samples in the (1 – x)BaTi<sub>4</sub>O<sub>9</sub>–xBaPr<sub>2</sub>Ti<sub>4</sub>O<sub>12</sub> system; backscattering electron image of (a)  $x = 0.36$ , and (b)  $x = 0.77$ .

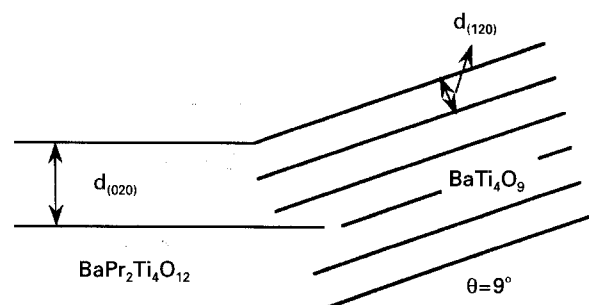
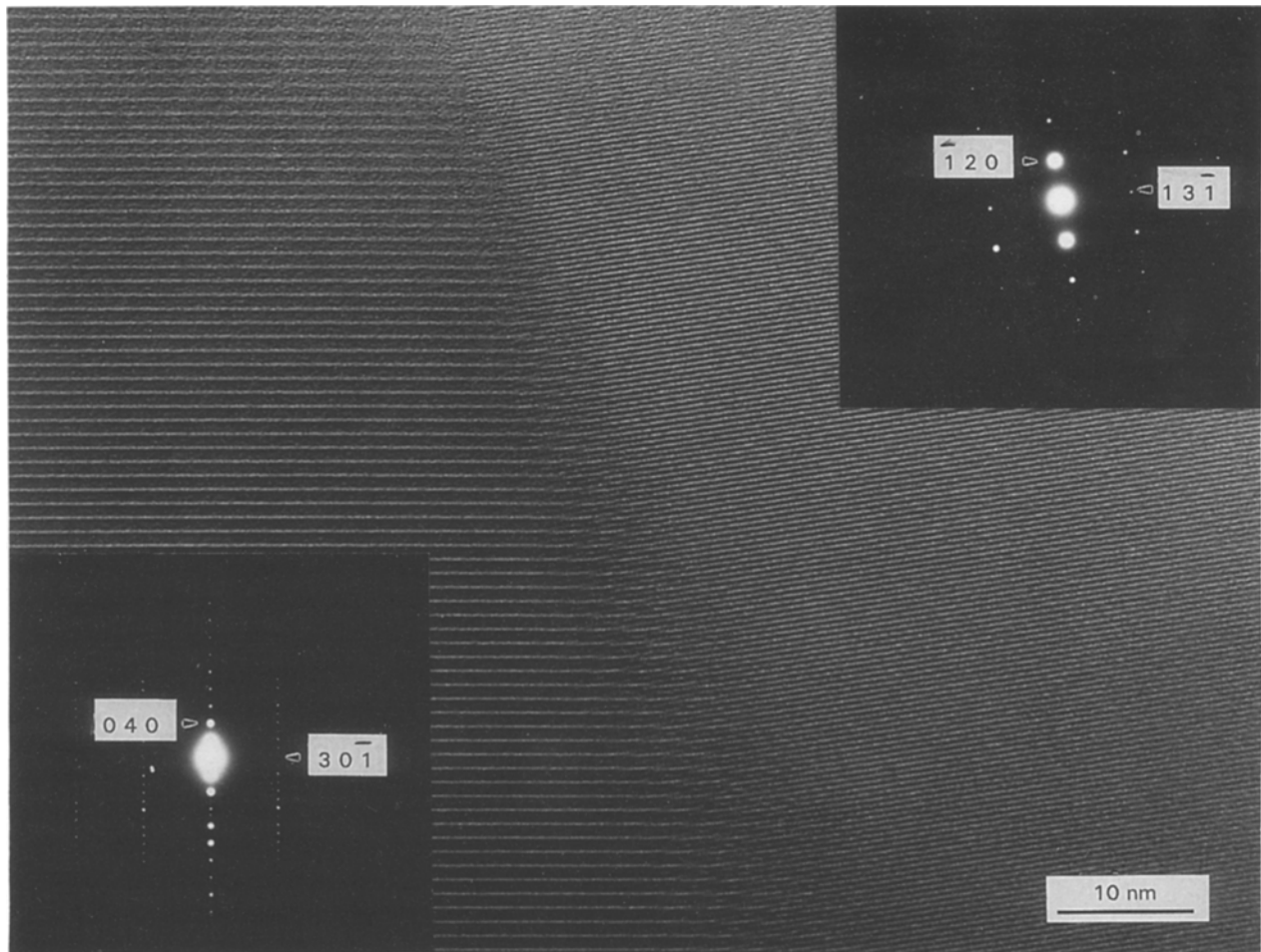


Figure 3 TEM photographs of ceramic sample ( $x = 0.36$  in Fig. 1).

These results correspond well with the XRD data displayed in Fig. 1. Of particular interest is the behaviour at the interface of two phases seen by transmission electron microscopy (TEM), as shown in Fig. 3 by electron diffraction images of the ceramic sample ( $x = 0.36$  in Fig. 1). In contrast with expectations that the interface of each phase consists of a disturbed array of atoms, with a thickness of a few nanometres, the lattices of each phase are well matched obliquely (about  $9^\circ$ ); i.e. double widths of the (020) plane for  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  are nearly equivalent to the five-fold widths of the (120) plane for  $\text{BaTi}_4\text{O}_9$  at the interface (this observation can also be supported by a simple calculation using each lattice parameter,  $d_{(020)} = 1.115$  nm [15] and  $d_{(120)} = 0.47574$  nm). Although it is necessary to observe various points in the ceramics for the matched interface, this fact may be related to the result that each phase can preserve its properties at the sintering temperature in this system.

### 3.2. Microwave properties and mixing relation

As shown in Figs 1 and 2, the system  $\text{BaTi}_4\text{O}_9$ – $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  ceramics is entirely composed of two phases, and in such a case it should be possible to predict the dielectric properties of the mixtures from dielectric properties of each component. The empirical models for predicting dielectric constants [4], temperature coefficients [4] and  $Q$  values [5] are expressed as follows

$$\ln \varepsilon = V_1 \ln \varepsilon_1 + V_2 \ln \varepsilon_2 \quad (6)$$

$$\tau = V_1 \tau_1 + V_2 \tau_2 \quad (7)$$

$$1/Q = V_1/Q_1 + V_2/Q_2 \quad (8)$$

where  $V_1$  and  $V_2$  are the volume fractions of the two components;  $\varepsilon_1$  and  $\varepsilon_2$  are their dielectric constants, while  $\varepsilon$  is the resultant dielectric constant of the

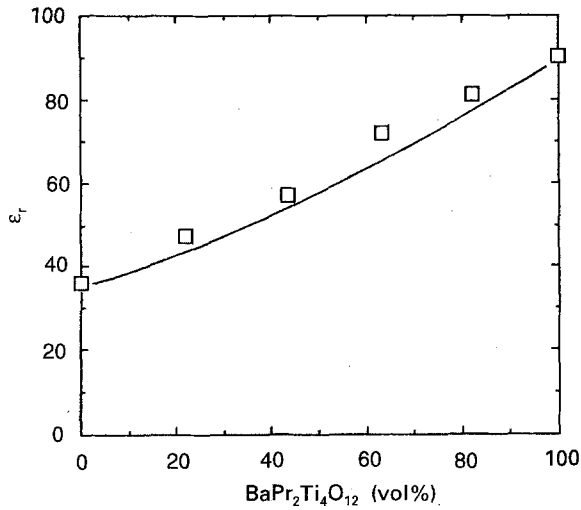


Figure 4 Room temperature dielectric constant,  $\epsilon_r$ , versus volume fraction of  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  in the  $\text{BaTi}_4\text{O}_9$ - $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  system. The solid curve represents values from the mixing relation, Equation 6.

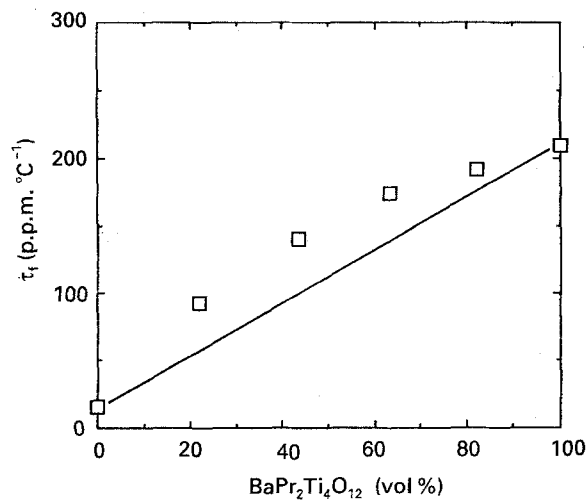


Figure 5  $\tau_f$  versus volume fraction of  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  in the  $\text{BaTi}_4\text{O}_9$ - $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  system. The solid line represents values from the mixing relation, Equation 7.

mixture;  $\tau_f$  is the temperature coefficient; and  $Q_1$  and  $Q_2$  are the  $Q$  values of the two components. The room temperature dielectric constants,  $\epsilon_r$ , the temperature coefficient of resonant frequency,  $\tau_f$ , and  $Q$  values are shown in Figs 4–6, respectively, compared with those obtained from the mixing relations, Equations 6–8. The volume fraction of each component is calculated on the assumption that the ceramic samples are perfectly composed of  $\text{BaTi}_4\text{O}_9$  and  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$ . From Fig. 6 it is found that the values of the measured  $Q$  values lie on the curve calculated from Equation 8, which indicates that this equation, for representing the mixing relation for  $Q$  values, is effective for predicting that of the mixture. On the other hand, the values of dielectric constants, and particularly those of  $\tau_f$ , fail to fall on the curves calculated from Equations 6 and 7. Though the origin of this result is now uncertain, it is considered that formation of the solid solution expressed by the general formula  $\text{Ba}_{6-y}$

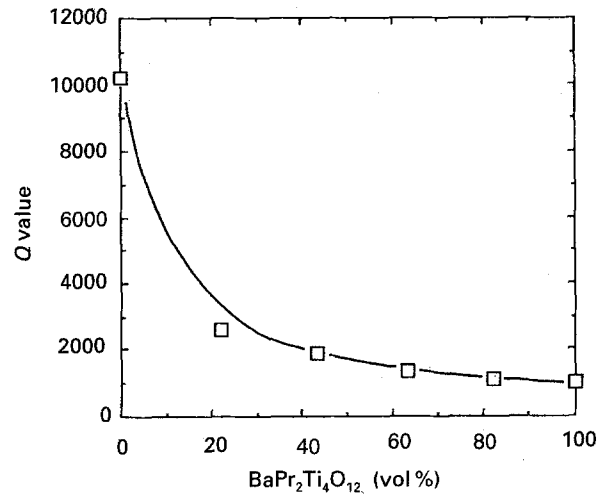


Figure 6  $Q$  value versus volume fraction of  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  in the  $\text{BaTi}_4\text{O}_9$ - $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  system. The solid curve represents values from the mixing relation, Equation 8.

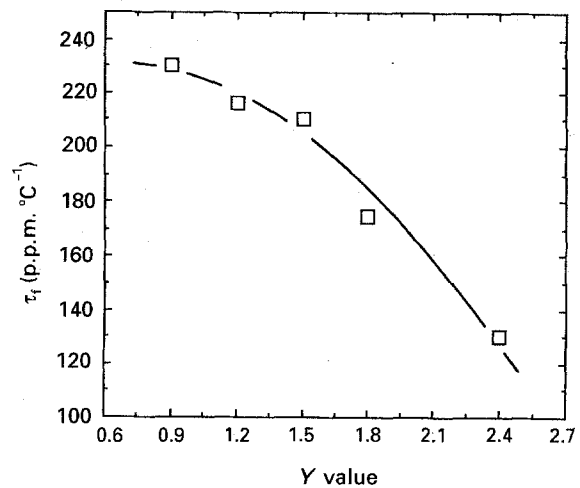


Figure 7  $\tau_f$  of  $\text{Ba}_{6-y}\text{Pr}_{8+2/3y}\text{Ti}_{18}\text{O}_{54}$  ceramics.

$\text{Pr}_{8+2y/3}\text{Ti}_{18}\text{O}_{54}$  [16] is strongly concerned with this result. The phase  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  is the intermediate composition of  $y = 1.5$  in this formula. Obtained was the experimental result that  $\tau_f$  for  $\text{Ba}_{6-y}\text{Pr}_{8+2/3y}\text{Ti}_{18}\text{O}_{54}$  ceramics rapidly increases with the decrease in  $y$  value, maintaining the same crystal structure as shown in Fig. 7. Accordingly, it is deduced that  $\text{Ba}_{6-y}\text{Pr}_{8+2/3y}\text{Ti}_{18}\text{O}_{54}$  ceramics ( $y < 1.5$ ) with higher  $\tau_f$  compared to the  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  ceramic, was formed in the vicinity of  $x = 0.5$  in the  $(1-x)$ - $\text{BaTi}_4\text{O}_9$ - $x\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  ceramic system. It is necessary to investigate this phenomenon in more detail.

### 3.3. Infrared reflection analysis

So far, the reflectance spectra of dielectric materials were usually analysed according to the classical dispersion theory or to the Kramers-Kronig relation [11, 17–19], and these results suggest that infrared reflectance spectroscopy could be used for the characterization of dielectric ceramics. This technique was applied with the factorized model described in

TABLE I Frequencies and damping parameters of three ceramics as deduced from the best fit to the reflectivity data

j	BaPr <sub>2</sub> Ti <sub>4</sub> O <sub>12</sub>					0.64BaPr <sub>2</sub> Ti <sub>4</sub> O <sub>12</sub> -0.36BaTi <sub>4</sub> O <sub>9</sub>					BaTi <sub>4</sub> O <sub>9</sub>				
	$\Omega_{j10}$ (cm <sup>-1</sup> )	$\gamma_{j10}$ (cm <sup>-1</sup> )	$\Omega_{j10}$ (cm <sup>-1</sup> )	$\gamma_{j10}$ (cm <sup>-1</sup> )	$\Omega_{j10}$ (cm <sup>-1</sup> )	$\Omega_{j10}$ (cm <sup>-1</sup> )	$\gamma_{j10}$ (cm <sup>-1</sup> )	$\Omega_{j10}$ (cm <sup>-1</sup> )	$\gamma_{j10}$ (cm <sup>-1</sup> )	$\Omega_{j10}$ (cm <sup>-1</sup> )	$\Omega_{j10}$ (cm <sup>-1</sup> )	$\gamma_{j10}$ (cm <sup>-1</sup> )	$\Omega_{j10}$ (cm <sup>-1</sup> )	$\gamma_{j10}$ (cm <sup>-1</sup> )	$\Omega_{j10}$ (cm <sup>-1</sup> )
1	77.0	14.1	78.9	13.0	60.7	3.0	61.5	3.0	60.0	61.0	1.0	61.0	1.0	61.0	1.0
2	91.6	17.9	100.0	16.5	76.8	6.5	81.4	6.5	75.1	80.4	4.0	80.4	4.0	80.4	4.0
3	116.0	24.7	121.2	22.0	91.1	12.0	98.3	12.0	82.7	85.9	4.0	85.9	4.0	85.9	4.0
4	135.7	32.7	154.2	30.0	121.7	27.0	124.1	27.0	99.4	103.4	5.0	103.4	5.0	103.4	5.0
5	173.8	40.5	187.0	40.0	138.9	53.0	159.0	53.0	147.9	148.0	33.0	148.0	33.0	148.0	33.0
6	204.0	43.4	225.7	43.1	170.2	45.9	183.6	45.9	160.9	161.8	10.0	161.8	10.0	161.8	10.0
7	234.3	44.5	269.0	45.0	209.9	19.1	214.2	18.1	169.2	177.8	12.9	177.8	12.9	177.8	12.9
8	274.0	29.5	280.5	30.1	229.1	18.2	246.2	21.0	212.0	212.7	6.1	212.7	6.1	212.7	6.1
9	284.5	29.5	306.7	29.5	259.9	15.0	263.8	15.0	230.5	238.4	7.2	238.4	7.2	238.4	7.2
10	314.6	31.0	340.5	31.0	269.9	17.0	281.4	17.0	243.6	246.1	5.0	246.1	5.0	246.1	5.0
11	341.8	34.5	379.2	34.5	288.1	18.5	309.3	14.5	259.9	267.2	10.0	267.2	10.0	267.2	10.0
12	384.3	33.0	407.5	34.0	314.3	17.0	326.7	23.0	286.5	309.5	15.0	309.5	15.0	309.5	15.0
13	409.5	39.0	441.5	36.5	332.8	45.0	370.2	49.5	317.0	319.5	9.0	319.5	9.0	319.5	9.0
14	448.4	35.0	486.0	35.5	387.7	43.8	406.0	43.5	327.7	343.0	23.0	343.0	23.0	343.0	23.0
15	490.0	41.0	499.0	42.0	427.2	38.0	449.8	32.0	376.8	400.0	37.8	400.0	37.8	400.0	37.8
16	542.5	42.0	552.0	40.0	453.1	27.0	476.0	27.0	436.2	460.2	27.0	460.2	27.0	460.2	27.0
17	567.0	53.5	617.0	51.0	487.0	32.0	503.3	32.0	467.8	478.0	30.0	478.0	30.0	478.0	30.0
18	618.5	40.5	712.5	40.5	511.2	26.6	530.5	26.2	492.6	527.3	23.6	527.3	23.6	527.3	23.6
19	717.5	44.0	764.2	55.0	543.3	28.0	553.1	29.0	535.6	552.4	24.0	552.4	24.0	552.4	24.0
20	819.0	64.0	838.0	67.0	546.2	39.5	627.5	50.2	560.2	605.5	27.0	605.5	27.0	605.5	27.0
21					625.7	50.0	626.4	52.3	625.7	626.2	50.0	626.2	50.0	626.2	50.0
22					639.9	50.0	735.5	52.0	632.6	742.5	86.0	742.5	86.0	742.5	86.0
23					736.6	40.0	761.9	53.0	746.1	752.1	51.0	752.1	51.0	752.1	51.0
24					791.6	78.0	824.5	72.0	758.1	828.5	77.0	828.5	77.0	828.5	77.0
25					920.2	69.5	936.5	67.5	920.2	949.5	74.5	949.5	74.5	949.5	74.5

$\epsilon_{\infty} = 5.09$

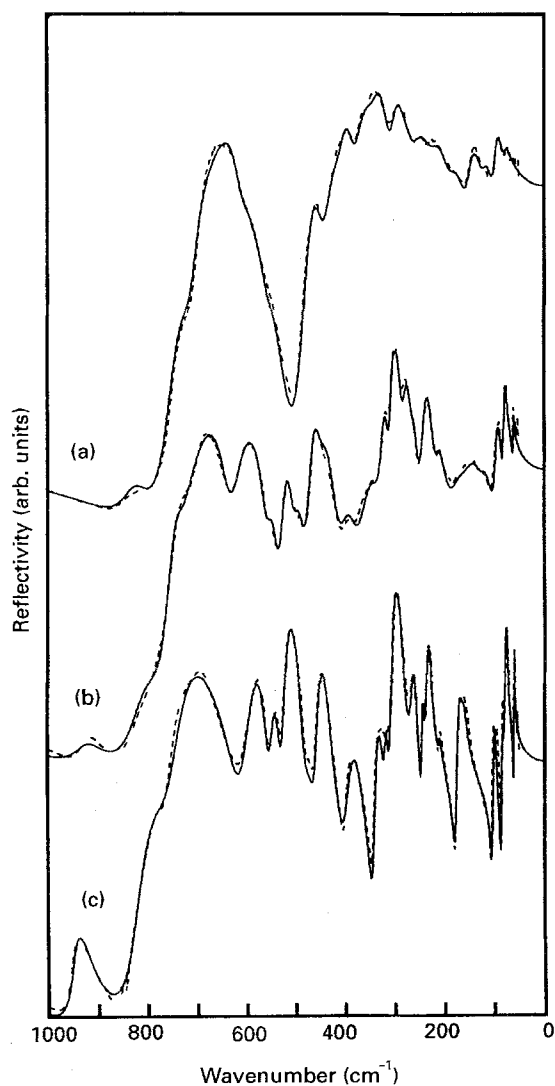
$\epsilon_{\infty} = 4.04$

$\epsilon_{\infty} = 4.80$

TABLE II Calculated  $\Delta\epsilon_j$  and  $\tan\delta_j$  for each TO mode

$j$	$\text{BaPr}_2\text{Ti}_4\text{O}_{12}$		$0.64\text{BaPr}_2\text{Ti}_4\text{O}_{12}-0.36\text{BaTi}_4\text{O}_9$		$\text{BaTi}_4\text{O}_9$	
	$\Delta\epsilon_j^a$	$\tan\delta_j^b (\times 10^{-3})$	$\Delta\epsilon_j$	$\tan\delta_j (\times 10^{-3})$	$\Delta\epsilon_j$	$\tan\delta_j (\times 10^{-3})$
1	8.20	0.03589	2.19	0.00529	1.76	0.0020
2	20.68	0.08117	9.87	0.03217	6.92	0.0219
3	9.62	0.03251	6.91	0.02954	0.89	0.0023
4	17.57	0.05740	2.97	0.01604	1.68	0.0038
5	9.04	0.02231	12.06	0.09797	0.05	0.0003
6	10.47	0.02009	2.56	0.01201	0.68	0.0017
7	4.49	0.00669	1.70	0.00218	2.91	0.0059
8	0.81	0.00585	4.36	0.00447	0.29	0.0001
9	1.11	0.00745	1.37	0.00090	3.14	0.0019
10	1.39	0.00803	2.14	0.00147	0.44	0.0001
11	0.17	0.00093	1.67	0.00110	1.83	0.0012
12	0.31	0.00129	0.58	0.00029	3.62	0.0029
13	0.09	0.00041	0.71	0.00086	0.23	0.0000
14	0.18	0.00058	0.61	0.00053	0.93	0.0008
15	0.02	0.00008	1.05	0.00065	1.93	0.0023
16	0.43	0.00112	0.16	0.00006	2.16	0.0013
17	0.78	0.00239	0.28	0.00011	0.39	0.0002
18	0.03	0.00006	0.21	0.00006	1.13	0.0004
19	0.02	0.00002	0.23	0.00007	0.32	0.0001
20	0.04	0.00007	0.40	0.00015	0.33	0.0001
21			0.00	0.00000	0.03	0.0000
22			0.15	0.00006	0.57	0.0005
23			0.00	0.00000	0.01	0.0000
24			0.04	0.00001	0.04	0.0000
25			0.04	0.00001	0.08	0.0000

<sup>a</sup> Calculated using Equation 3. <sup>b</sup> Calculated using Equation 5 for each TO mode at 5 GHz.



Section 2, instead of the classical dispersion theory to the material system composed of mixed phases mentioned above. Fig. 8a–c demonstrates the measured and calculated reflectance spectra of  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$ ,  $0.64\text{BaTi}_4\text{O}_9-0.36\text{BaPr}_2\text{Ti}_4\text{O}_{12}$ , and  $\text{BaTi}_4\text{O}_9$  ceramics, respectively. The solid lines show the calculated reflectivity, which are in good agreement with the observed ones (dashed lines) for the three ceramics. An attempt was also made to fit the reflectivity data with the classical dispersion theory, but the calculated reflectivities data did not fit the observed ones well; which suggests that vibrational modes with different energy levels should not be equally damped [8]. Table I shows the frequencies and damping parameters deduced from the best fit of the reflectivity data for these ceramics, and Table II summarizes  $\Delta\epsilon_j$  and  $\tan\delta_j$  calculated using Equations 3 and 5. In  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  ceramics, the observed reflectance spectrum was found to be well fitted by using 20 phonons in total (Fig. 8a). It was found that six phonons ( $j = 1-6$ ) having low resonant frequencies of  $80-220\text{ cm}^{-1}$  had large oscillator strength ( $\Delta\epsilon_j > 8$ ), and thus contributed significantly to dielectric loss at microwave frequencies. In a previous work [20] where measurement of the reflectance spectrum of  $\text{BaPr}_2\text{Ti}_5\text{O}_{14}$  ceramics, whose crystal structure was analogous to that of  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$ , 18 infrared modes were observed. The general appearance of the  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  ceramics spectrum is similar to that of  $\text{BaPr}_2\text{Ti}_5\text{O}_{14}$ , but the  $\text{BaPr}_2\text{Ti}_5\text{O}_{14}$  peaks located at  $200-400\text{ cm}^{-1}$  are

Figure 8 Measured (---) and calculated (—) reflectivity for (a)  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$ , (b)  $0.64\text{BaTi}_4\text{O}_9-0.36\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  and (c)  $\text{BaTi}_4\text{O}_9$  ceramics.

sharper than those of the  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  ceramics. In  $0.64\text{BaTi}_4\text{O}_9-0.36\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  ceramics, it is found that three phonons ( $j = 2, 3, 5$ ) have great strength ( $\Delta\epsilon_j > 6$ ) and resonant frequencies were shifted to relatively higher frequencies compared with those of the  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  ceramics. This observation can be seen clearly from Fig. 9, where computed  $\epsilon''$  as a function of frequency is shown. On the other hand, the observed reflectance spectrum of the  $\text{BaTi}_4\text{O}_9$  ceramics was found to be well fitted using 25 phonons in total (Fig. 8b), and many resonances ( $j = 1, 2, 4, 9, 11, 12, 15, 16, 18$ ), with the same degree of intensity and damping, are distributed in a wide range of lower to higher frequencies (50 to  $500\text{ cm}^{-1}$ ) as shown in Fig. 9.

The room temperature dielectric constant,  $\epsilon_r$  and  $Q$  from Equations 1 and 4 are compared with those obtained from direct measurements at 5 GHz in Table III for three ceramics. The calculated dielectric constant agree well with the measured values, and the calculated  $Q$  values are to some extent larger than the measured ones for the  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  and  $0.64\text{BaTi}_4\text{O}_9-0.36\text{BaPr}_2\text{Ti}_4\text{O}_{12}$

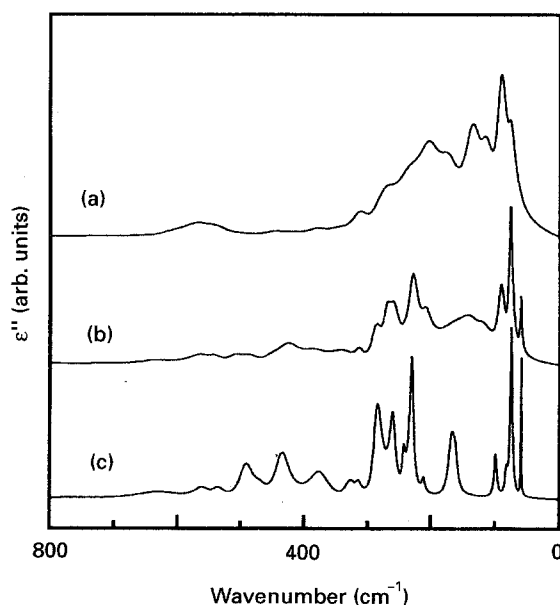


Figure 9 Computed  $\epsilon''$  as a function of frequency for (a)  $\text{BaPr}_2\text{Ti}_4\text{O}_{12}$ , (b)  $0.64\text{BaTi}_4\text{O}_9-0.36\text{BaPr}_2\text{Ti}_4\text{O}_{12}$ , and (c)  $\text{BaTi}_4\text{O}_9$  ceramics.

TABLE III Measured and calculated dielectric characteristics at 5 GHz

Material	Measured		Calculated	
	$\epsilon_r$	$Q$ (at 5 GHz)	$\epsilon_r$	$Q$ (at 5 GHz)
$\text{BaTi}_4\text{O}_9$	35	10200	37	9700
$0.64\text{BaTi}_4\text{O}_9-0.36\text{BaPr}_2\text{Ti}_4\text{O}_{12}$	57	1890	56	4200
$\text{BaPr}_2\text{Ti}_4\text{O}_{12}$	91	1000	90	2300

ceramics. The origin of the difference in  $Q$  values may be the result of an error in the reflectance measurements, due to factors such as scattering from porosity and scratches on the ceramic samples, as reported by Mhaisalkar *et al.* [18]. Though such problems must be solved for better estimation, it is suggested that this method of reflection analysis can be applied to such ceramic materials composed of mixed phases for investigating the dielectric properties.

#### 4. Conclusions

The microwave characteristics of the system  $\text{BaTi}_4\text{O}_9-\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  were investigated, including its microstructure and infrared reflection spectroscopy. The following results were obtained.

1. The system  $\text{BaTi}_4\text{O}_9-\text{BaPr}_2\text{Ti}_4\text{O}_{12}$  is entirely composed of two phases, and it is suggested that the lattices of each phase are well matched obliquely at the interface in the sintered ceramics.
2. The mixing relation for  $Q$  values can be well applied to this system.
3. It would be possible to investigate the dielectric properties of ceramic materials composed of mixed phases by means of infrared reflection analysis.

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